

2019 29th RCJ EOS/ESD/EMC Symposium Program

November 27(Wednesday) 2019 : 10:20~19:00

Place: 4th Floor Convention Hole (A)

(10:20~10:25)	Opening Address	Noboru Shiono (RCJ)
(10:25~10:30)	Introduction of EOS/ESD/EMC Symposium	Teruo Suzuki (Socionext)

Session: 「Device &Test」		Chairman : Akira Oyama (Sony)
(10:30~10:55)	29E-01	「Consideration on Acquisition Method of Voltage Waveform During CDM Test」 Masanori Sawada (HEI)
(10:55~11:20)	29E-02	「Powerclamp ESD performance under powered & unpowered condition」 Hiroyasu Ishizuka (Synaptics Japan)
(11:20~11:45)	29E-03	「2nd Discharge Current Waveform Measurement during System Level ESD Test」 Satoshi Isofuku (TET)
Award Ceremony		
(11:45~12:00)		Award Ceremony
Break (12:00~13:15)		
Invited talks		Chairman : Teruo Suzuki (Socionext)
(13:15~13:50)	Invited	ESDA 2018 EOS/ESD Symposium Best Paper 「Device Failure from the Initial Current Step of a CDM Discharge」 ○David Johnsson, Krzysztof Domanski, Harald Gossner (Intel Deutschland GmbH)
Invited talks		Chairman : Hiroyasu Ishizuka (Synaptics Japan)
(13:50~14:50)	Invited	「Electrical Overstress EOS: Design for Mitigation」 Charvaka Duvvury (ESD Consulting LLC and iT2 Technologies)
Break (15:00~15:20)		
Session: 「ESD Control」		Chairman : Masanori Sawada (HEI) , Shuji Fujiwara (ON semiconductor)
(15:20~15:45)	29E-04	「Countermeasures against electrostatic damage (ESD) in pure water spray cleaning during flat panel display manufacturing」 Yasuaki Fukuoka (Aichi Institute of Technology)
(15:45~16:10)	29E-05	「Visualization of ESD phenomenon」 Kenichi Kawabe*, Osamu Ochi*, Hideaki Tokunaga**, Tatsuya Inoue** (*O-K-Sha Kagoshima Co., Ltd, **Panasonic Corporation)
(16:10~16:35)	29E-06	「Study of charge in surface potential during neutralization」 Yoshiaki Miyamoto (HEI)
(16:35~17:00)	29E-07	「Study of suppression Cable Discharge Events (CDE)」 Misa Konno, Kenji nakajima, Tsuyoshi ito (Japan Aerospace Exploration Agency Safety and Mission Assurance Department)
Welcome party (for all attendees) (17:15~19:00)		

November 28(Thursday) 2019 : 9:50~17:30

Place: 4th Floor Convention Hole (A)

Session: 「Device &Test」		Chairman : Hideaki Tokunaga (Panasonic)
(9:50~10:15)	29E-08	「A Variable VH Combined Power Clamp for System Level ESD/Surge Immunity Enhancement with Low Leakage」 Koki Narita, Mototsugu Okushima (Renesas Electronics)
(10:15~10:40)	29E-09	「CDM Measurement for Bare Dies and Wafers」 Teruo Suzuki*, Kazuya Okubo*, Hiroki Taniguchi*, Masanori Sawada**, Hiroyuki Okumura**, Kazuo Shinke** (*Socionext Inc., ** HANWA ELECTRONIC IND. CO., LTD.)
Break (10:40~10:50)		
Invited talks		Chairman : Mototsugu Okushima (Renesas)
(10:50~11:50)	Invited	「Electronic Design Automation Solutions for ESD and Latch-up」 Michael Khazhinsky (Silicon Labs)
Break (11:50~12:50)		
Invited talks		Chairman : Nobuyuki Wakai (Thosiba)
(12:50~13:40)	Invited	「Industry Council update」 Charvaka Duvvury (ESD Consulting LLC and iT2 Technologies)
seminar		Chairman : Satoshi Isofuku (TET)
(13:40~14:30)	Invited	「Report of RCJ Committee (ESD Model and ESD Control for Board-Module Level) 」 Yasuhiro Fukuda (ESD Consultant)
Break (14:30~14:40)		
Session: 「Immunity (1)」		Chairman : Masamitsu Honda (IPL), Takayoshi Ohtsu (Numazu National Courage of Technology)
(14:40~15:05)	29E-10	「Analysis of Electro-magnetic Noise caused by Human-body」 Yutaka Soda (Probetek)
(15:05~15:30)	29E-11	「Analysis of Malfunction of Robot by ESD using Optical Electric Field Sensor」 Takayoshi Ohtsu (Numazu National Courage of Technology)
(15:30~15:55)	29E-12	「Circuit Malfunction due to Radiated Transient Fields Generated by Small Gap ESD」 Masamitsu Honda (IPL)
(15:55~16:20)	29E-13	「Observation of electrostatic discharge phenomenon using Ultra-high sensitivity ultraviolet camera」 Takayoshi Ohtsu (Numazu National Courage of Technology)
Break (16:20~16:30)		
Invited talks		Chairman : Tadashi Ozawa (Megachips)
(16:30~17:30)	Invited	「ESD Simulation and Modeling」 Eugene R. Worley (Silicon Crossing, LLC)
Dinner party (for invited speakers and program committee members) (18:30~20:30)		